SDLS154 - OCTOBER 1975 - REVISED MARCH 1988

- 'LS295B Offers Three Times the Sink-Current Capability of 'LS295A
- Schottky-Diode-Clamped Transistors
- Low Power Dissipation . . . 80 mW Typical (Enabled)
- Applications:

N-Bit Serial-To-Parallel Converter N-Bit Parallel-To-Serial Converter N-Bit Storage Register

description

These 4-bit registers feature parallel inputs, parallel outputs, and clock (CLK), serial (SER), mode (LD/SH), and outputs control (OC) inputs. The registers have three modes of operation:

Parallel (broadside) load Shift right (the direction Q_A toward Q_D) Shift left (the direction Q_D toward Q_A)

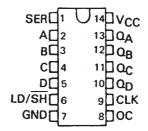
Parallel loading is accomplished by applying the four bits of data and taking the mode control input high. The data is loaded into the associated flip-flops and appears at the outputs after the high-to-low transition of the clock input. During parallel loading, the entry of serial data is inhibited.

Shift right is accomplished when the mode control is low; shift left is accomplished when the mode control is high by connecting the output of each flip-flop to the parallel input of the previous flip-flop (QD to input C, etc.) and serial data is entered at input D.

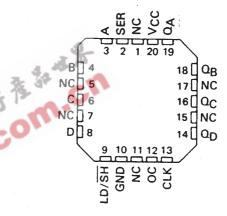
When the output control is high, the normal logic levels of the four outputs are available for driving the loads or bus lines. The outputs are disabled independently from the level of the clock by a low logic level at the output control input. The outputs then present a high impedance and neither load nor drive the bus line; however, sequential operation of the registers is not affected.

The SN54LS295B is characterized for operation over the full military temperature range of -55° C to 125°C; the SN74LS295B is characterized for operation from 0°C to 70°C.

SN54LS295B . . . J OR W PACKAGE SN74LS295B . . . D OR N PACKAGE (TOP VIEW)

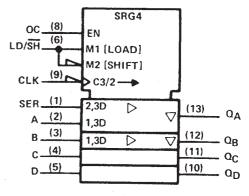


SN54LS295B . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

logic symbol†

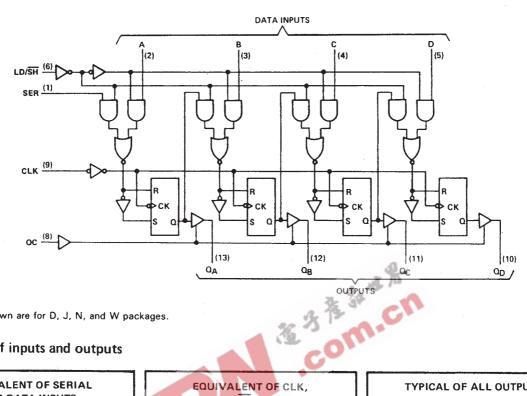


[†]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

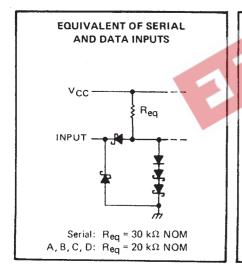
SN54LS295B, SN74LS295B 4-BIT RIGHT-SHIFT LEFT-SHIFT REGISTERS WITH 3-STATE OUTPUTS SDLS154 - OCTOBER 1975 - REVISED MARCH 1988

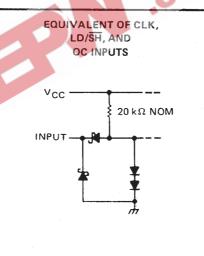
logic diagram (positive logic)

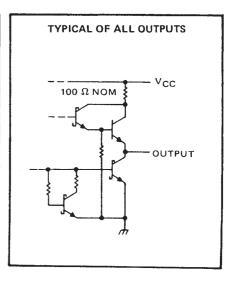


Pin numbers shown are for D, J, N, and W packages.

schematics of inputs and outputs







SN54LS295B, SN74LS295B 4-BIT RIGHT-SHIFT LEFT-SHIFT REGISTERS **WITH 3-STATE OUTPUTS**

SDLS154 - OCTOBER 1975 - REVISED MARCH 1988

FUNCTION TABLE

INPUTS						OUTPUTS					
4.5/50	CLK	SER	PARALLEL				0.	0-	0-	0-	
LD/SH			Α	В	С	D	Q _A	QΒ	σC	α _D	
H	Н	х	X	X	X	Х	Q _{A0}	Q _{B0}	a_{co}	σ_{D0}	
н	+	×	а	b	C	d	а	b	c	d	
н	↓	×	QBt	Q _C †	$a_D t$	d	QBn	Q_{Cn}	α_{Dn}	d,	
L	н	×	×	X	X	Х	Q _{A0}	Q_{B0}	σ_{CO}	Q_{D0}	
L	↓	н	×	X	X	X	н	\mathbf{Q}_{An}	Q_{Bn}	Q_{Cn}	
L	↓	L	×	X	X	X	L		α_{Bn}		

When the output control is low, the outputs are disabled to the high-impedance state; however, sequential operation of the registers is not affected.

H = high level (steau, state), L = low level (steady state), X = irrelevant (any input, including transitions)

↓ = transition from high to low level.

a, b, c, d = the level of steady-state input at inputs A, B, C, or D, respectively.

a, b, c, d = the level of steady-state input at inputs A, B, C, or D, respectively.

QAQ, QBQ, QCQ, QDQ = the level of QA, QB, QC, or QD, respectively, before the indicated steady-state input conditions were established.

QAn, QBn, QCn, QDn = the level of QA, QB, QC, or QD, respectively, before the most-recent \$\frac{1}{2}\$ transition of the clock.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)		 7 V
Input voltage		 7 V
Operating free-air temperature range:	SN54LS295B .	 5°C
	SN74LS295B	 0°C
Storage temperature range		 0°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

			St	SN54LS295B			SN74LS295B			
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.25	V	
ЮН	High-level output current				– 1			- 2.6	mA	
IOL	Low-level output current				12			24	mA	
fclock	Clock frequency		0		30	0		30	MHz	
tw(clock)	Width of clock pulse		16			16			ns	
t _{su}	Setup time, high-level or low-level data		20			20			ns	
	Setup time, LD/SH to CLK	high-level	25			25			l	
t _{su}	low-level		30			30			ns	
th	Hold time, high-level or low-level data		20			20			ns	
th	Hold time, high-level or low-level LD/SH to CLK		0			0			ns	
TA	Operating free-air temperature		- 55		125	0		70	°C	



 $^{^\}dagger$ Shifting left requires external connection of QB to A, QC to B, and QD to C. Serial data is entered at input D.

SN54LS295B, SN74LS295B 4-BIT RIGHT-SHIFT LEFT-SHIFT REGISTERS **WITH 3-STATE OUTPUTS**

SDLS154 - OCTOBER 1975 - REVISED MARCH 1988

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	242445752	confirmat			SN54LS295B			SN74LS295B			
PARAMETER		TEST CONDITIONS [†]			MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
V _{IH}	High-level input voltage				2			2			V
VIL	Low-level input voltage						0.7			0.8	V
VIK	Input clamp voltage	V _{CC} = MIN,	l ₁ = -18 mA				-1.5			-1.5	V
Voн	High-level output voltage	V _{CC} = MIN, V _{IL} = V _{IL} max,	V _{IH} = 2 V, I _{OH} = MAX		2.4	3.4		2.4	3.1		٧
1/	Law L	V _{CC} = MIN,	V _{IH} = 2 V,	1 _{OL} = 12 mA		0.25	0.4		0.25	0.4	V
VOL	Low-level output voltage	VIL = VIL max		1 _{OL} = 24 mA					0.35	0.5	\ \ \
1	Off-state output current,	V _{CC} = MAX,	VIL = VIL max,				20			20	
IOZH	high-level voltage applied	V _O = 2.7 V					20			20	μΑ
lozu	Off-state output current,	V _{CC} = MAX,	V _{IH} = 2 V,				20			20	
OZL	low-level voltage applied	V _O = 0.4 V					20			 20	μΑ
l _l	Input current at maximum input voltage	V _{CC} = MAX,	V ₁ = 7 V				0.1			0.1	mA
ЧН	High-level input current	V _{CC} = MAX,	V ₁ = 2.7 V			0	20			20	μА
HL	Low-level input current	V _{CC} = MAX,	V ₁ = 0.4 V			A /0	-0.4			-0.4	mA
los	Short-circuit output current §	V _{CC} = MAX		3	-30	-	-1 30	-30		-130	mA
loo	Supply current	V _{CC} = MAX,	See Note 2	Condition A	20 29		20	29			
1CC	oupply culterit		See Note 2	Condition B	-6	22	33		22	33	mA

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 2: ICC is measured with the outputs open, the serial input and mode control at 4.5 V, and the data inputs grounded under the following conditions:

- A. Output control at 4.5 V and a momentary 3 V, then ground, applied to clock input.
- B. Output control and clock input grounded.

switching characteristics, V_{CC} = 5 V, T_A = 25 C, R_L = 667 Ω

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{max} Maximum clock frequency		30	45	· · · · · · · · · · · · · · · · · · ·	MHz
tpLH Propagation delay time, low-to-high-level output	0 - 45 - 5		14	20	ns
tpHL Propagation delay time, high-to-low-level output	C _L = 45 pF,		19	30	ns
tpZH Output enable time to high level	See Note 3		18	26	ns
tPZL Output enable time to low level			20	30	ns
[†] PHZ Output disable time from high level	C _L = 5 pF,		13	20	ns
tPLZ Output disable time from low level	See Note 3		13	20	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



 $[\]ddagger$ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25 ^{\circ} \text{C}$.

[§] Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

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